

## FRIDAY AM

### XRD

#### STRESS ANALYSIS

EVERGREEN B

*Chairs:* C. Goldsmith, IBM, Hopewell Junction, NY

T. Watkins, Oak Ridge National Laboratory, Oak Ridge, TN

**8:30 D-50 Invited—Thermo-Mechanical Behavior of Thin Films and Small Structures Characterized by Synchrotron X-ray Diffraction**

J. Keckes, *University Leoben and Austrian Academy of Sciences, Leoben, Austria*

**9:00 D-48 XRD Stress Analyses on Surfaces with Curvature Radius below 1mm, a New Challenge!**

A. Haase, M. Klatt, A. Schafmeister, R. Stabenow, *GE Sensing & Inspection Technologies GmbH, Ahrensburg, Germany*

**9:20 D-101 Invited—A Next Generation Neutron Diffraction Strain Scanner for Steady-State Sources**

R.B. Rogge, *Canadian Neutron Beam Centre, National Research Council, Canada*

**9:50 Break**

**10:10 D-16 Invited—Commissioning Results and New Scientific Opportunities at Vulcan—The SNS Materials Science and Engineering Diffractometer**

K. An, X.-L. Wang, A.D. Stoica, H. Skorpenske, D. Ma, C.R. Hubbard, *Oak Ridge National Laboratory, Oak Ridge, TN*

T.M. Holden, *Northern Stress Technology, Deep River, Canada*

P.K. Liaw, H. Choo, *University of Tennessee, Knoxville, TN*

**10:40 D-96 In-Situ Neutron Diffraction Study of Residual Stress in Steel Ammonia Nurse Tank Welds**

T.A. Sisneros, D.W. Brown, *Los Alamos National Laboratory, Los Alamos, NM*

A. Russel, *Ames National Laboratory, Ames, IA*

S. Chumbley, A. Becker, *Iowa State University, Ames, IA*

## FRIDAY AM

### XRF

#### TRACE ANALYSIS

EVERGREEN C

*Chair:* P. Wobrauschek, Atominstytut, Vienna University of Technology, Vienna, Austria

**8:30 F-72 Invited—TXRF- A Versatile Tool for Trace Element Analysis: A Review**

P. Wobrauschek, *Atominstytut, Vienna Univ. of Technology, Vienna, Austria*

**9:00 F-31 Discovering the Selenium Metabolism and Its Impact for Health Prevention by TXRF**

A. Gross, H. Stosnach, *Bruker Nano GmbH, Berlin, Germany*

K. Renko, T. Behrends, L. Schomburg, *Charité Berlin, Berlin, Germany*

**9:20 F-76 Invited—Different Applications of Polycapillaries to X-ray Spectroscopy**

H.J. Sánchez, R.D. Pérez, *Universidad Nacional de Córdoba, Argentina*

C.A. Pérez, *Laboratório Nacional de Luz Síncrotron, Campinas, Brasil*

**9:50 F-33 Trace Element Detection Using Monochromatic Wavelength Dispersive X-ray Fluorescence**

G.J. Havrilla, M. Collins, V. Montoya, *Los Alamos National Laboratory, Los Alamos, NM*

Z. Chen, F. Wei, *X-ray Optical Systems, East Greenbush, NY*

**10:10 Break**